

# A School of Engineering Seminar San Francisco State University

## Waveform Analysis Challenges for the Multi-Gigabit/sec Digital Communications Era



SF STATE

**Jeff Most,**

Keysight Technology  
(Spin-off from Agilent/HP)

**Dec. 1, 2014  
Monday**

**1.10-2pm**

**SCI 256**

### **Synopsis:**

Today's high speed serial data communications continue to provide ever faster data transfer by increasing both baud rate and modulation complexity. For engineers developing and validating new designs, the most commonly used measurement tool is the high bandwidth Oscilloscope. Bandwidths exceed 50 GHz, through either direct analog to digital conversion at up to 160 Gigasamples/s or through a lower cost approach employing a synchronous triggering scheme. This session will explain the fundamentals of both real-time and equivalent-time sampling oscilloscopes and explain how the unique benefits of each help to address the measurement challenges of today's high speed digital designs.

### **Speaker Bio:**

**Jeff Most** is a Product Marketing Engineer for Equivalent Time Sampling Oscilloscopes at the Oscilloscope and Protocol Division of Keysight Technologies, a spin-off of Agilent Technologies. Jeff has a Bachelor of Science degree in electrical engineering from the State University of New York at Buffalo and over 15 years of experience in high speed communications and signal integrity in various roles at Hewlett Packard Test and Measurement, Agilent Technologies and Keysight technologies.

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